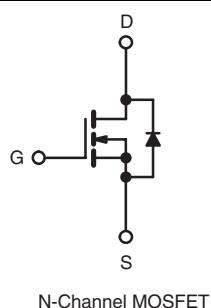
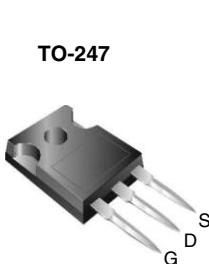


Power MOSFET

PRODUCT SUMMARY	
V _{DS} (V)	600
R _{DS(on)} (Ω)	V _{GS} = 10 V 0.18
Q _g (Max.) (nC)	180
Q _{gs} (nC)	56
Q _{gd} (nC)	86
Configuration	Single



FEATURES

- Low Gate Charge Q_g Results in Simple Drive Requirement
- Improved Gate, Avalanche and Dynamic dV/dt Ruggedness
- Fully Characterized Capacitance and Avalanche Voltage and Current
- Enhanced Body Diode dV/dt Capability
- Lead (Pb)-free Available

APPLICATIONS

- Hard Switching Primary or PFC Switch
- Switch Mode Power Supply (SMPS)
- Uninterruptible Power Supply
- High Speed Power Switching
- Motor Drive

ORDERING INFORMATION

Package	TO-247
Lead (Pb)-free	IRFP27N60KPbF SiHFP27N60K-E3
SnPb	IRFP27N60K SiHFP27N60K

ABSOLUTE MAXIMUM RATINGS T _C = 25 °C, unless otherwise noted				
PARAMETER		SYMBOL	LIMIT	UNIT
Drain-Source Voltage		V _{DS}	600	
Gate-Source Voltage		V _{GS}	± 30	V
Continuous Drain Current	V _{GS} at 10 V	T _C = 25 °C	I _D	27
		T _C = 100 °C		18
Pulsed Drain Current ^a		I _{DM}	110	A
Linear Derating Factor			4.0	W/°C
Single Pulse Avalanche Energy ^b		E _{AS}	530	mJ
Repetitive Avalanche Current ^a		I _{AR}	27	A
Repetitive Avalanche Energy ^a		E _{AR}	50	mJ
Maximum Power Dissipation	T _C = 25 °C	P _D	500	W
Peak Diode Recovery dV/dt ^c		dV/dt	13	V/ns
Operating Junction and Storage Temperature Range		T _J , T _{stg}	- 55 to + 150	°C
Soldering Recommendations (Peak Temperature)	for 10 s		300 ^d	
Mounting Torque	6-32 or M3 screw		10	lbf · in
			1.1	N · m

Notes

- Repetitive rating; pulse width limited by maximum junction temperature (see fig. 11).
 - Starting T_J = 25 °C, L = 1.4 mH, R_G = 25 Ω, I_{AS} = 27 A, dV/dt = 13 V/ns (see fig. 12).
 - I_{SD} ≤ 27 A, dI/dt ≤ 390 A/μs, V_{DD} ≤ V_{DS}, T_J ≤ 150 °C.
 - 1.6 mm from case.
- * Pb containing terminations are not RoHS compliant, exemptions may apply

THERMAL RESISTANCE RATINGS

PARAMETER	SYMBOL	TYP.	MAX.	UNIT
Maximum Junction-to-Ambient	R_{thJA}	-	40	$^{\circ}\text{C}/\text{W}$
Case-to-Sink, Flat, Greased Surface	R_{thCS}	0.24	-	
Maximum Junction-to-Case (Drain)	R_{thJC}	-	0.29	

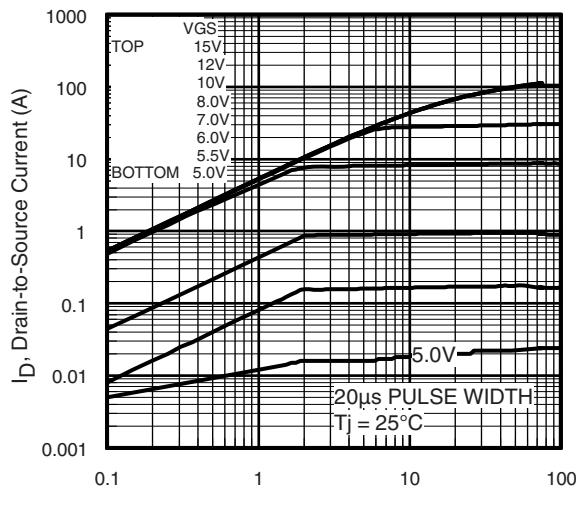
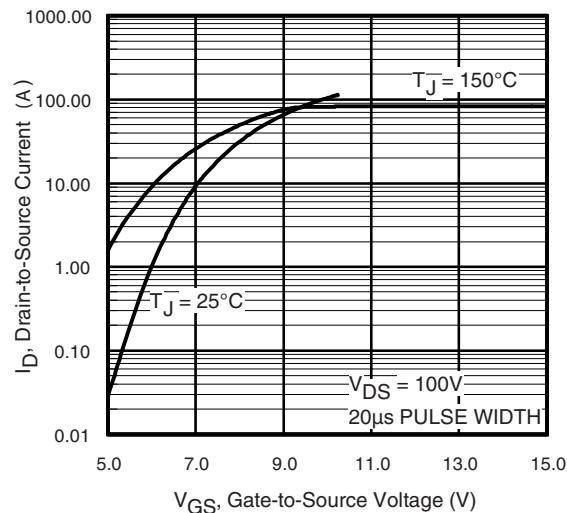
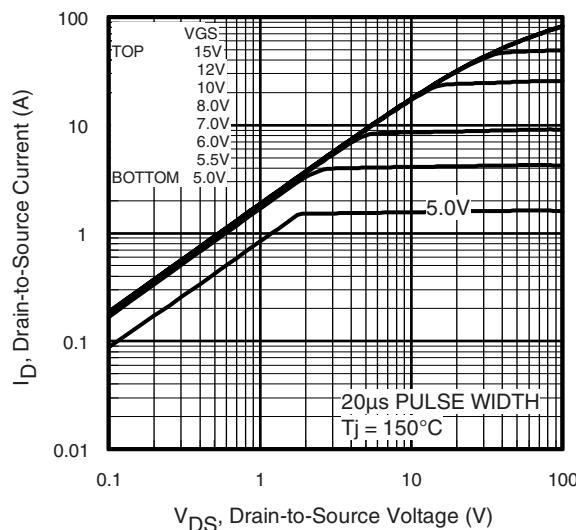
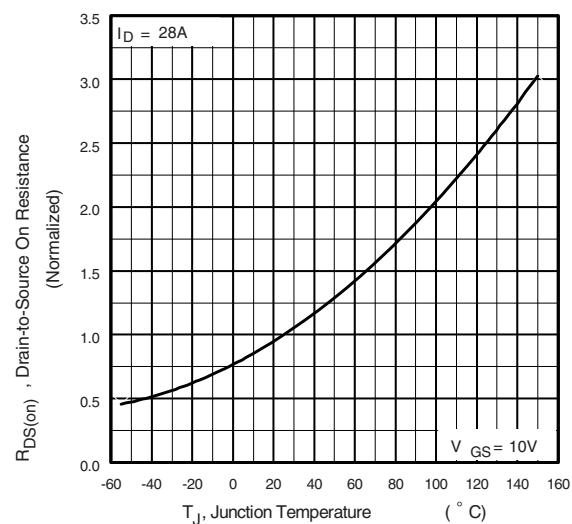
SPECIFICATIONS $T_J = 25^{\circ}\text{C}$, unless otherwise noted

PARAMETER	SYMBOL	TEST CONDITIONS		MIN.	TYP.	MAX.	UNIT	
Static								
Drain-Source Breakdown Voltage	V_{DS}	$V_{GS} = 0 \text{ V}$	$I_D = 250 \mu\text{A}$	600	-	-	V	
V_{DS} Temperature Coefficient	$\Delta V_{DS}/T_J$	Reference to 25°C , $I_D = 1 \text{ mA}$		-	640	-	$\text{mV}/^{\circ}\text{C}$	
Gate-Source Threshold Voltage	$V_{GS(th)}$	$V_{DS} = V_{GS}$, $I_D = 250 \mu\text{A}$		3.0	-	5.0	V	
Gate-Source Leakage	I_{GSS}	$V_{GS} = \pm 30 \text{ V}$		-	-	± 100	nA	
Zero Gate Voltage Drain Current	I_{DSS}	$V_{DS} = 600 \text{ V}$, $V_{GS} = 0 \text{ V}$		-	-	50	μA	
		$V_{DS} = 480 \text{ V}$, $V_{GS} = 0 \text{ V}$, $T_J = 125^{\circ}\text{C}$		-	-	250		
Drain-Source On-State Resistance	$R_{DS(on)}$	$V_{GS} = 10 \text{ V}$	$I_D = 16 \text{ A}^b$	-	0.18	0.22	Ω	
Forward Transconductance	g_{fs}	$V_{DS} = 50 \text{ V}$, $I_D = 16 \text{ A}$		14	-	-	S	
Dynamic								
Input Capacitance	C_{iss}	$V_{GS} = 0 \text{ V}$		-	4660	-	pF	
Output Capacitance	C_{oss}			-	460	-		
Reverse Transfer Capacitance	C_{rss}			-	41	-		
Output Capacitance	C_{oss}	$V_{GS} = 0 \text{ V}$	$V_{DS} = 1.0 \text{ V}$, $f = 1.0 \text{ MHz}$	-	5490	-		
		$V_{GS} = 0 \text{ V}$	$V_{DS} = 480 \text{ V}$, $f = 1.0 \text{ MHz}$	-	120	-		
Effective Output Capacitance	$C_{oss eff.}$	$V_{GS} = 0 \text{ V}$	$V_{DS} = 0 \text{ V}$ to 480 V	-	250	-		
Total Gate Charge	Q_g	$V_{GS} = 10 \text{ V}$	$I_D = 27 \text{ A}$, $V_{DS} = 480 \text{ V}$ see fig. 6 and 13 ^b	-	-	180	nC	
Gate-Source Charge	Q_{gs}			-	-	56		
Gate-Drain Charge	Q_{gd}			-	-	86		
Turn-On Delay Time	$t_{d(on)}$	$V_{DD} = 300 \text{ V}$, $I_D = 27 \text{ A}$ $R_G = 4.3 \Omega$, $V_{GS} = 10 \text{ V}$, see fig. 10 ^b		-	27	-	ns	
Rise Time	t_r			-	110	-		
Turn-Off Delay Time	$t_{d(off)}$			-	43	-		
Fall Time	t_f			-	38	-		
Drain-Source Body Diode Characteristics								
Continuous Source-Drain Diode Current	I_S		$T_J = 25^{\circ}\text{C}$, $I_S = 27 \text{ A}$, $V_{GS} = 0 \text{ V}^b$	-	-	27	A	
Pulsed Diode Forward Current ^a	I_{SM}			-	-	110		
Body Diode Voltage	V_{SD}	$T_J = 25^{\circ}\text{C}$, $I_F = 27 \text{ A}$, $dI/dt = 100 \text{ A}/\mu\text{s}^b$		-	-	1.5	V	
Body Diode Reverse Recovery Time	t_{rr}			-	620	920	ns	
Body Diode Reverse Recovery Charge	Q_{rr}			-	11	16	μC	
Reverse Recovery Current	I_{RRM}			-	36	53	A	
Forward Turn-On Time	t_{on}	Intrinsic turn-on time is negligible (turn-on is dominated by L_S and L_D)						

Notes

a. Repetitive rating; pulse width limited by maximum junction temperature (see fig. 11).

b. Pulse width $\leq 300 \mu\text{s}$; duty cycle $\leq 2\%$.c. $C_{oss eff.}$ is a fixed capacitance that gives the same charging time as C_{oss} while V_{DS} is rising from 0 to 80% V_{DS} .

TYPICAL CHARACTERISTICS 25 °C, unless otherwise noted

Fig. 1 - Typical Output Characteristics

Fig. 3 - Typical Transfer Characteristics

Fig. 2 - Typical Output Characteristics

Fig. 4 - Normalized On-Resistance vs. Temperature

IRFP27N60K, SiHFP27N60K



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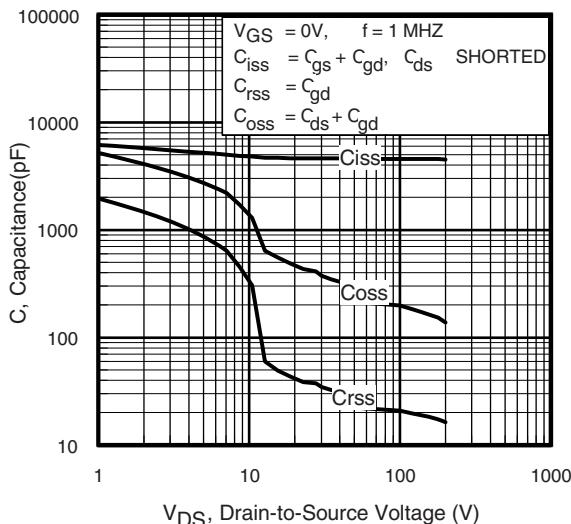


Fig. 5 - Typical Capacitance vs. Drain-to-Source Voltage

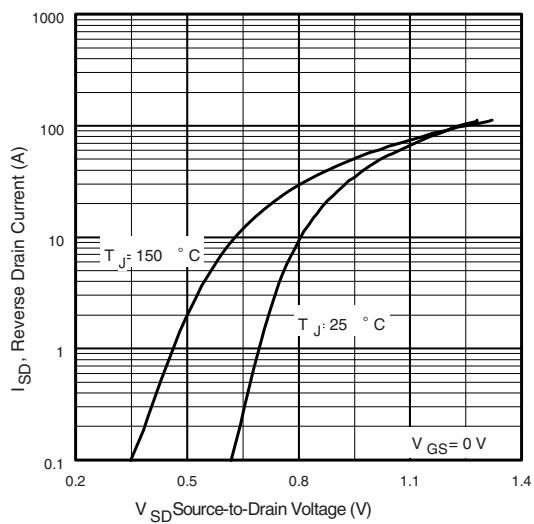


Fig. 7 - Typical Source-Drain Diode Forward Voltage

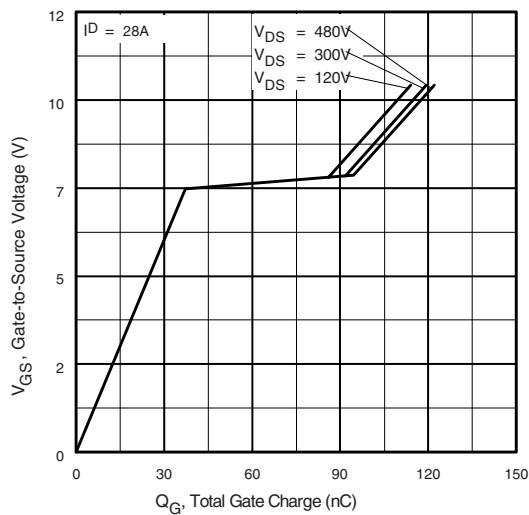


Fig. 6 - Typical Gate Charge vs. Gate-to-Source Voltage

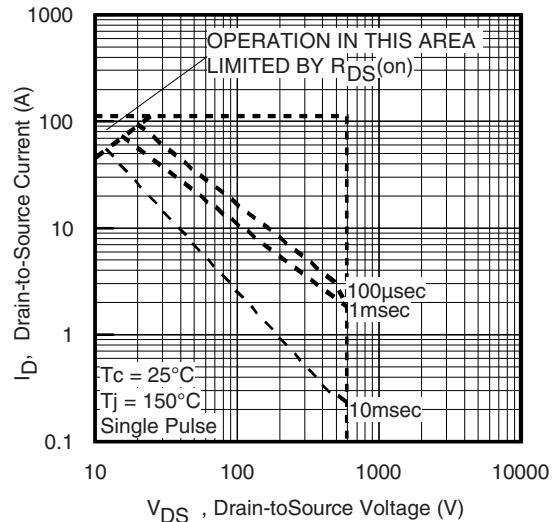


Fig. 8 - Maximum Safe Operating Area

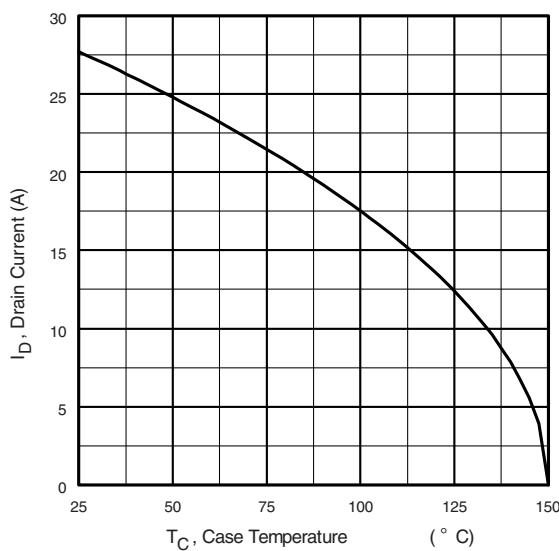


Fig. 9 - Maximum Drain Current vs. Case Temperature

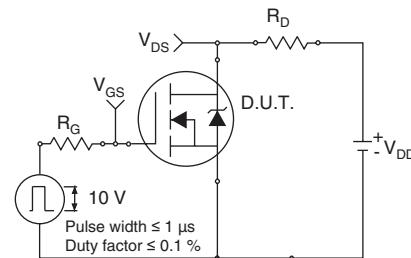


Fig. 10a - Switching Time Test Circuit

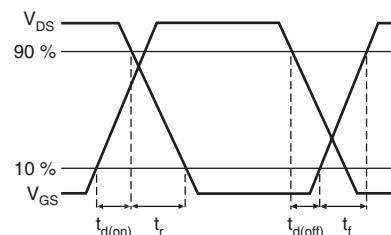


Fig. 10b - Switching Time Waveforms

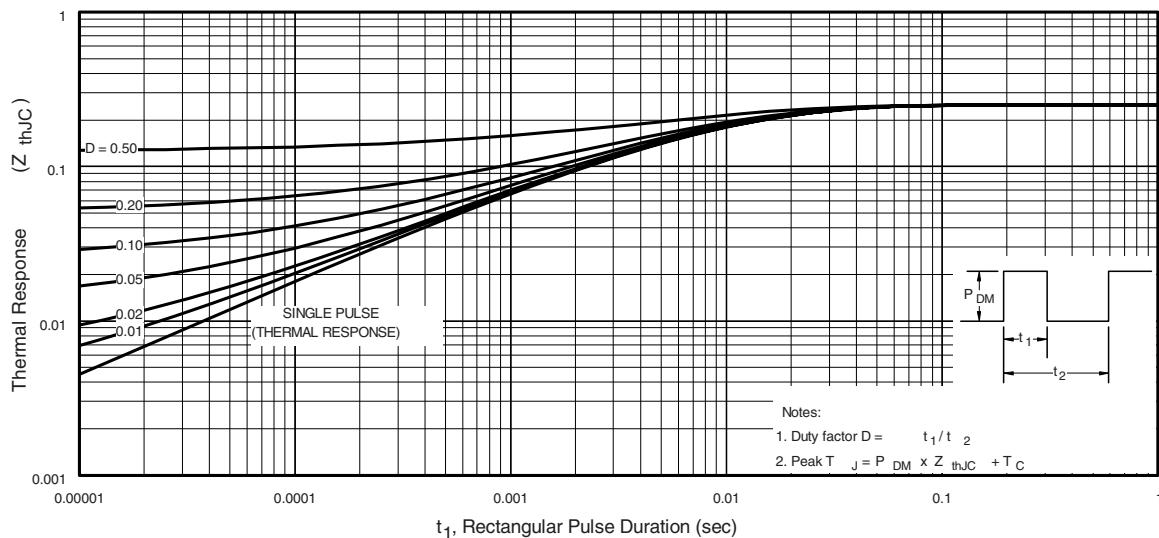


Fig. 11 - Maximum Effective Transient Thermal Impedance, Junction-to-Case

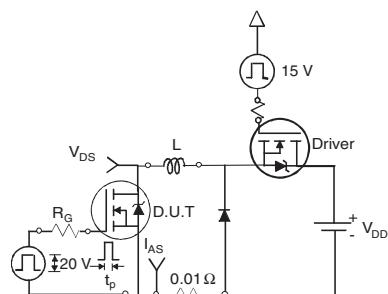


Fig. 12a - Unclamped Inductive Test Circuit

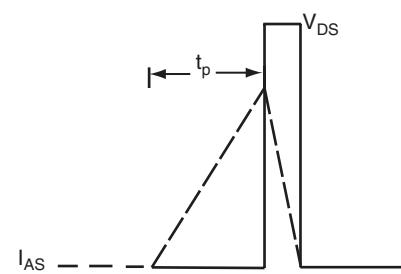


Fig. 12b - Unclamped Inductive Waveforms

IRFP27N60K, SiHFP27N60K

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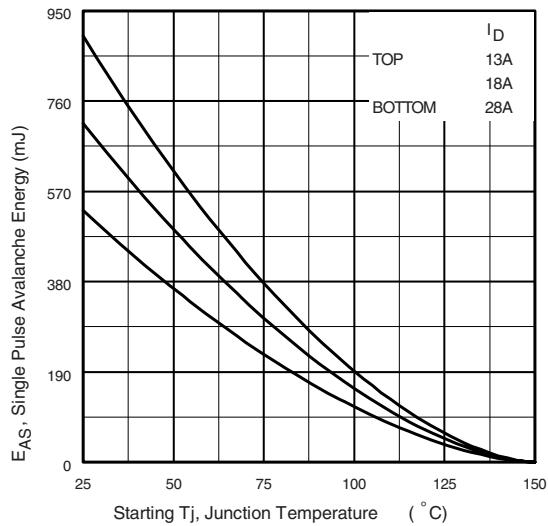


Fig. 12c - Maximum Avalanche Energy vs. Drain Current

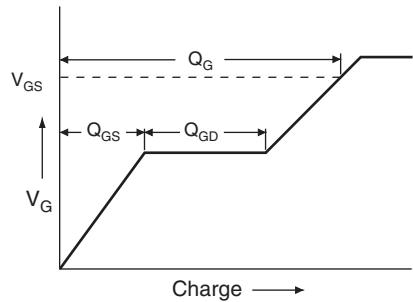


Fig. 13a - Basic Gate Charge Waveform

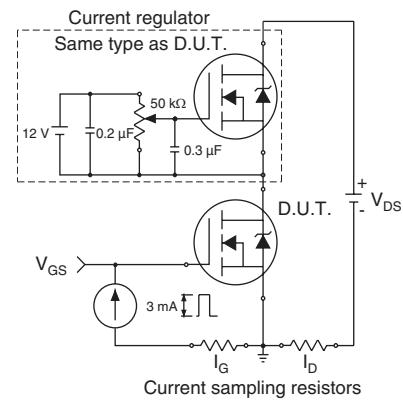
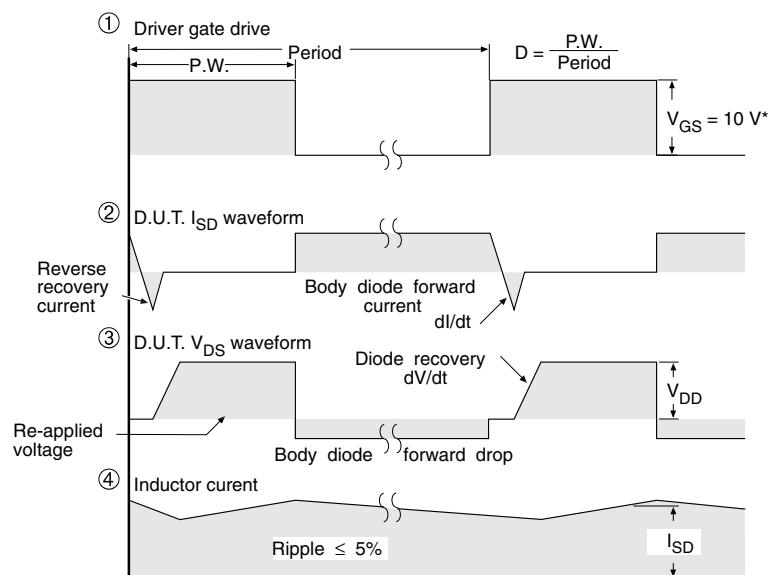
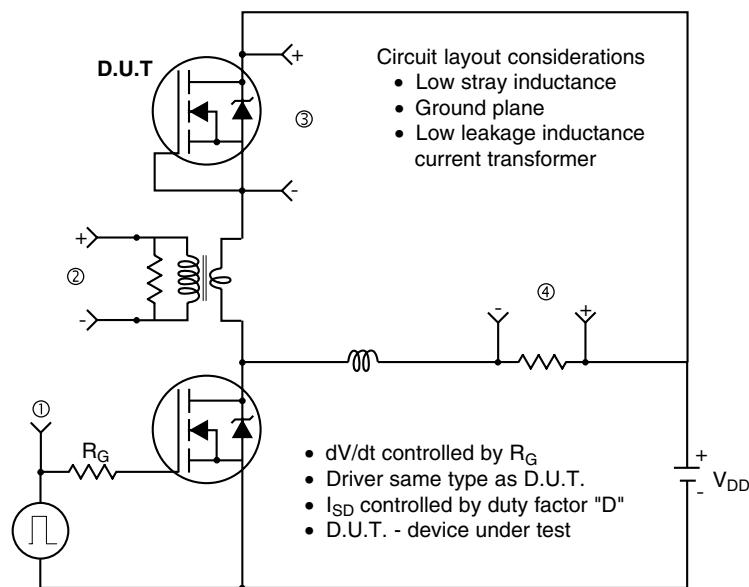


Fig. 13b - Gate Charge Test Circuit

Peak Diode Recovery dV/dt Test Circuit



* $V_{GS} = 5$ V for logic level devices

Fig. 14 - For N-Channel

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